
Connectors for electronic equipment - Tests and measurements - Part 1-2: General examination - Test 1b: Examination of dimension and mass (IEC 60512-1-2:2002)

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English version

**Connectors for electronic equipment –
Tests and measurements
Part 1-2: General examination –
Test 1b: Examination of dimension and mass
(IEC 60512-1-2:2002)**

Connecteurs pour équipements
électroniques –
Essais et mesures
Partie 1-2: Examen général –
Essai 1b: Examen de dimension
et masse
(CEI 60512-1-2:2002)

Steckverbinder für elektronische
Einrichtungen –
Mess- und Prüfverfahren
Teil 1-2: Allgemeine Untersuchungen –
Prüfung 1b: Maß- und Gewichtsprüfung
(IEC 60512-1-2:2002)

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CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

Foreword

The text of document 48B/1129/FDIS, future edition 1 of IEC 60512-1-2, prepared by SC 48B, Connectors, of IEC TC 48, Electromechanical components and mechanical structures for electronic equipment, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 60512-1-2 on 2002-04-01.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2003-01-01
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2005-04-01

Endorsement notice

The text of the International Standard IEC 60512-1-2:2002 was approved by CENELEC as a European Standard without any modification.

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**Connecteurs pour équipements électroniques –
Essais et mesures –**

**Partie 1-2:
Examen général –
Essai 1b: Examen de dimension et masse**

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**Connectors for electronic equipment –
Tests and measurements –**

**Part 1-2:
General examination –
Test 1b: Examination of dimension and mass**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**CONNECTORS FOR ELECTRONIC EQUIPMENT –
TESTS AND MEASUREMENTS –****Part 1-2: General examination –
Test 1b: Examination of dimension and mass**

FOREWORD

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International Standard IEC 60512-1-2 has been prepared by subcommittee 48B: Connectors, of IEC technical committee 48: Electromechanical components and mechanical structures for electronic equipment.

This standard cancels and replaces test 1b of IEC 60512-2, issued in 1985, and constitutes a technical revision.

The text of this standard is based on the following documents:

FDIS	Report on voting
48B/1129/FDIS	48B/1180/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 3.

The committee has decided that the contents of this publication will remain unchanged until 2007. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

CONNECTORS FOR ELECTRONIC EQUIPMENT – TESTS AND MEASUREMENTS –

Part 1-2: General examination – Test 1b: Examination of dimension and mass

1 Scope and object

This part of IEC 60512, when required by the detail specification, is used for testing electromechanical components within the scope of IEC technical committee 48. This test may also be used for similar devices when specified in a detail specification.

The object of this test is to define a standard test method for the examination of dimension and mass of electromechanical components.

2 General

The dimensional examination and checking of mass are measurements made on the actual parts with the aid of suitable measuring tools and measuring equipment in compliance with the relevant specification.

3 Features to be checked

3.1 Outline dimensions

Dimensions shall be checked and shall comply with the outline drawings of the detail specification.

3.2 Mass

The mass shall be checked and shall comply with the detail specification.

3.3 Clearance and creepage

Clearance and creepage distances shall be checked when specified by the detail specification. The distances shall be in accordance with the requirements of the appropriate general requirements documents.

3.4 Detailed dimensions

When required by the detail specification, detailed dimensions of the components supplied shall be checked and shall comply with the relevant drawings.

3.5 Gauging procedure

Where gauging procedures are specified by the detail specification, the relevant specimens shall be accepted or rejected by the gauges, as appropriate.

3.6 Special measurements

Special measurements such as:

- measurements of the thickness of protection,
- measurements of surface roughness or irregularities,

are not covered by this standard.

4 Measuring methods

The examination of dimensions and checking of mass shall be carried out with appropriate measuring equipment, for example:

- a) a vernier gauge, a micrometer and a dial gauge;
- b) gauges;
- c) a measuring projector with a suitable linear magnification;
- d) a measuring microscope;
- e) a balance.

5 Details to be specified

When this test is required by the detail specification, the following details shall be specified:

- a) features to be checked;
 - b) gauging details, if applicable; [SIST EN 60512-1-2:2003](https://standards.itec.ai/catalog/standards/sist/dfe94d60-ef8c-4252-aa19-05aba5c09788/iec-60512-1-2-2003)
 - c) type and magnification of measuring equipment; <https://standards.itec.ai/catalog/standards/sist/dfe94d60-ef8c-4252-aa19-05aba5c09788/iec-60512-1-2-2003>
 - d) deficiency criteria;
 - e) any deviation from the standard test method.
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